

Sophisticated Instrumentation Centre (SIC)
Four Probe Hall Measurement System
Indian Institute of Technology Indore

Instrument: *Four Probe Hall Measurement System*

DATE:

1. NAME OF ORGANISATION:

2. NAME OF USER:

3. NAME OF THE GUIDE/PI:

4. ADDRESS/DEPARTMENT:

5. E-MAIL:

CONTACT NO. / FAX. NO.:

Information regarding the sample to measure

Previous characterizations performed for the sample:

Description about the sample:

Number of samples:

Thin film materials to measure:

Thickness of thin films on substrate:

Estimated surface roughness of thin film:

Substrate:

Substrate dimension and shape:

Any other information:

Use of ***Four Probe Hall Measurement System*** at IIT Indore automatically implies that following acknowledgement will be given by the user whenever either oral or written presentations are made of the results obtained from the facility:

“We are grateful to the “**Four Probe Hall Measurement System equipped at Sophisticated Instrument Centre (SIC), IIT Indore.**” Further, the user must ensure to send us copies of reprints of publications which contain results obtained from above facility.

Signature of Guide/Coordinator/Supervisor/User
Date